Methods of High-Pressure Single-Crystal X-ray Diffraction

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Technical challenges

Overview of methods

Overview of the workshop



Single crystal and powder

- Single-crystal data is 3 dimensional not 1 dimensional, intrinsically superior to powder diffraction:
 - No peak overlaps
 - No resolution problems
 - No preferred orientation problems
 - No "powder average" problems
 - Signal to noise is higher
- □ Single crystal diffraction allows:
 - **The unambiguous determination of minute structural changes**
 - The determination of small structural distortions (phase transitions)
 - Acentric crystals
 - Measurement of diffuse scattering and incommensurate structures
 - Reliable displacement parameters

"A bad single crystal is better than a good powder" (McMahon)



Aim of the workshop is to show you 'how'





The Diamond Anvil Cell





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Diamond-anvil geometry





Transmission mode



Cell parameters at high pressure

Precise diffraction angle data to measure small changes in cell parameters at high pressures:





Tiziana: today and tomorrow



Determining structures at high pressure

Workflow is similar to crystals in air





Limited access





Miletich, RiM volume

Fewer reflections means:

- more sensitivity to individual data
- higher chance of systematic error
- higher influence of random error
- less resolution



Reducing background

Everything you see is background!



Conventional DAC with Be seats, steel gasket

DAC with steel seats and rhenium gasket



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Determining structures at high pressure

- Because of the challenges:
 - Optimise the data collection





Reducing background

Use a point detector:

Additional collimation



- Optimised scan speed
- Step scans
- Profile fitting
- Recovery of weak data





Data collection at synchrotron sources



Indexing and integration

- □ Similar to crystals in air
 - But tricks and software to overcome the challenges



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Software Fayre: today

Intensity data



Absorption





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Ross: tomorrow



Refinement



Post-refinement analysis



Workshop overview



